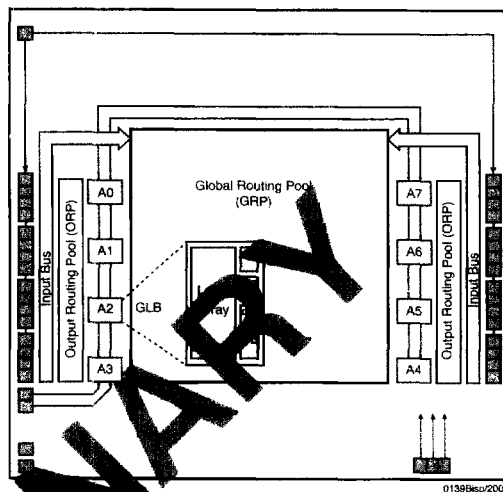


Features

- **SuperFAST HIGH DENSITY IN-SYSTEM PROGRAMMABLE LOGIC**
 - 1000 PLD Gates
 - 32 I/O Pins, Two Dedicated Inputs
 - 32 Registers
 - High Speed Global Interconnect
 - Wide Input Gating for Fast Counters, State Machines, Address Decoders, etc.
 - Small Logic Block Size for Random Logic
 - 100% Functional/JEDEC Upward Compatible with ispLSI 2032V Devices
- **3.3V LOW VOLTAGE 2032 ARCHITECTURE**
 - Interfaces With Standard 5V TTL Devices
 - 80 mA Typical Active Current
 - Fuse Map Compatible with 5V ispLSI 2032 and 2032E
- **HIGH PERFORMANCE E²CMOS[®] TECHNOLOGY**
 - f_{max} = 200 MHz Maximum Operating Frequency
 - t_{pd} = 4.0 ns Propagation Delay
 - Electrically Erasable and Reprogrammable
 - Non-Volatile
 - 100% Tested at Time of Manufacture
- **IN-SYSTEM PROGRAMMABLE**
 - 3.3V In-System Programmability Using Boundary Scan Test Access Port (TAP)
 - Open-Drain Output Option for Flexible Bus Interface Capability, Allowing Easy Implementation of Wired-OR or Bus Arbitration Logic (2032V)
 - Increased Manufacturing Yield, Reduced Time-to-Market and Improved Product Quality
- **100% IEEE 1149.1 BOUNDARY SCAN TESTABLE**
- **THE EASE OF USE AND FAST IN-SYSTEM SPEED OF PLDs WITH THE DENSITY AND FLEXIBILITY OF FPGAs**
 - Enhanced Pin Labeling Capability
 - Three Dedicated Clock Input Pins
 - Synchronous and Asynchronous Clocks
 - Programmable Output Slew Rate Control
 - Flexible Pin Placement
 - Optimized Global Routing Pool Provides Global Interconnectivity
- **ispEXPERT™ – LOGIC COMPILER AND COMPLETE ISP DEVICE DESIGN SYSTEMS FROM HDL SYNTHESIS THROUGH IN-SYSTEM PROGRAMMING**
 - Superior Quality of Results
 - Tightly Integrated with Leading CAE Vendor Tools
 - Productivity Enhancing Timing Analyzer, Explore Tools, Timing Simulator and ispANALYZER™
 - PC and UNIX Platforms

Functional Block Diagram



Description

The ispLSI 2032VE is a High Density Programmable Logic Device that can be used in both 3.3V and 5V systems. The device contains 32 Registers, 32 Universal I/O pins, two Dedicated Input Pins, three Dedicated Clock Input Pins, one dedicated Global OE input pin and a Global Routing Pool (GRP). The GRP provides complete interconnectivity between all of these elements. The ispLSI 2032VE features in-system programmability through the Boundary Scan Test Access Port (TAP) and is 100% IEEE 1149.1 Boundary Scan Testable. The ispLSI 2032VE offers non-volatile reprogrammability of the logic, as well as the interconnect to provide truly reconfigurable systems.

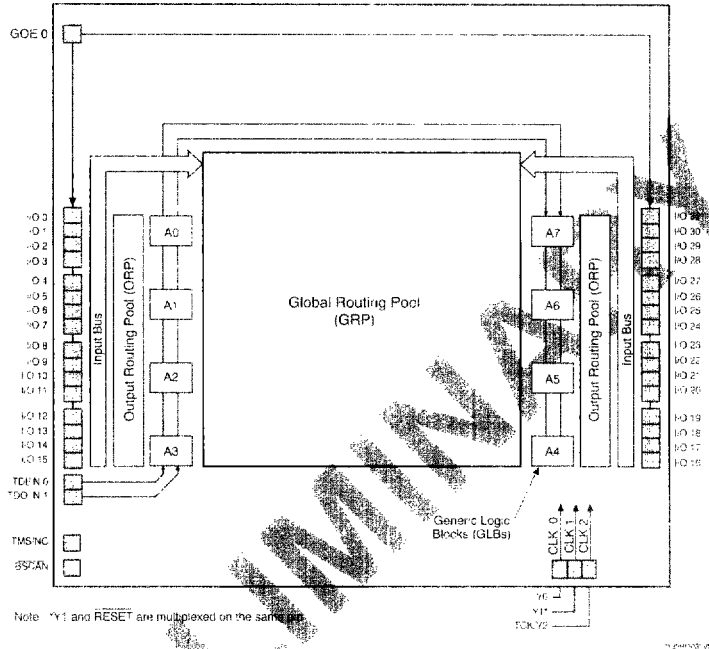
The basic unit of logic on the ispLSI 2032VE device is the Generic Logic Block (GLB). The GLBs are labeled A0, A1 .. A7 (see Figure 1). There are a total of eight GLBs in the ispLSI 2032VE device. Each GLB is made up of four macrocells. Each GLB has 18 inputs, a programmable AND/OR/Exclusive OR array, and four outputs which can be configured to be either combinatorial or registered. Inputs to the GLB come from the GRP and dedicated inputs. All of the GLB outputs are brought back into the GRP so that they can be connected to the inputs of any GLB on the device.

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Functional Block Diagram

Figure 1. ispLSI 2032VE Functional Block Diagram



The device also has 32 I/O cells, each of which is directly connected to an I/O pin. Each I/O cell can be individually programmed to be a combinational input, output or bi-directional I/O pin with 3-state control. The signal levels are TTL compatible voltages, and the output drivers can source 4 mA or sink 8 mA. Each output can be programmed independently for fast or slow output slew rate to minimize overall output switching noise. Device pins can be safely driven to 5 Volt signal levels to support mixed-voltage systems.

Eight GLBs, 32 I/O cells, two dedicated inputs and two ORPs are connected together to make a Megablock (see Figure 1). The outputs of the eight GLBs are connected to a set of 32 universal I/O cells by the ORP. Each ispLSI 2032VE device contains one Megablock.

The GRP has as its inputs the outputs from all of the GLBs and all of the inputs from the bi-directional I/O cells. All of these signals are made available to the inputs of the GLBs. Delays through the GRP have been equalized to minimize timing skew.

Clocks in the ispLSI 2032VE device are selected using the dedicated clock pins. Three dedicated clock pins (Y0, Y1, Y2) or an asynchronous clock can be selected on a GLB basis. The asynchronous or Product Term clock can be generated in any GLB for its own clock.

Programmable Open-Drain Outputs

In addition to the standard output configuration, the outputs of the ispLSI 2032VE are individually programmable, either as a standard totem-pole output or an open-drain output. The totem-pole output drives the specified V_{oh} and V_{ol} levels, whereas the open-drain output drives only the specified V_{ol} . The V_{oh} level on the open-drain output depends on the external loading and pull-up. This output configuration is controlled by a programmable fuse. When this fuse is erased (JEDEC "1"), the output is configured as a totem-pole output. When this fuse is programmed (JEDEC "0"), the output is configured as an open-drain. The default configuration when the device is in bulk erased state is totem-pole configuration. The open-drain/totem-pole option is selectable through the ispEXPERT software tools.

External Timing Parameters

Over Recommended Operating Conditions

PARAMETER	TEST COND. ⁴	# ²	DESCRIPTION ¹	-200		-180		UNITS
				MIN.	MAX.	MIN.	MAX.	
t _{pd1}	A	1	Data Propagation Delay, 4PT Bypass, ORP Bypass	—	4.0	—	5.0	ns
t _{pd2}	A	2	Data Propagation Delay	—	5.5	—	7.5	ns
f _{max}	A	3	Clock Frequency with Internal Feedback ³	200	—	180	—	MHz
f _{max} (Ext.)	—	4	Clock Frequency with External Feedback ($\frac{1}{t_{su2} + t_{oc1}}$)	154	—	125	—	MHz
f _{max} (Tog.)	—	5	Clock Frequency, Max. Toggle	250	—	200	—	MHz
t _{su1}	—	6	GLB Reg. Setup Time before Clock, 4 PT Bypass	2.5	—	3.0	—	ns
t _{co1}	A	7	GLB Reg. Clock to Output Delay, ORP Bypass	—	—	—	4.0	ns
t _{h1}	—	8	GLB Reg. Hold Time after Clock, 4 PT Bypass	—	—	0.0	—	ns
t _{su2}	—	9	GLB Reg. Setup Time before Clock	2.5	—	4.0	—	ns
t _{co2}	—	10	GLB Reg. Clock to Output Delay	—	4.0	—	4.5	ns
t _{h2}	—	11	GLB Reg. Hold Time after Clock	0.0	—	0.0	—	ns
t _{r1}	A	12	Ext. Reset Pin to Output Delay	—	5.0	—	7.0	ns
t _{rw1}	—	13	Ext. Reset Pulse Duration	3.5	—	4.0	—	ns
t _{ptoen}	B	14	Input to Output Enable	—	7.0	—	10.0	ns
t _{ptoedis}	C	15	Input to Output Disable	—	7.0	—	10.0	ns
t _{goeen}	B	16	Global OE Output Enable	—	3.5	—	5.0	ns
t _{goedis}	C	17	Global OE Output Disable	—	3.5	—	5.0	ns
t _{wh}	—	18	External Synchronous Clock Pulse Duration, High	2.0	—	2.5	—	ns
t _{wl}	—	19	External Synchronous Clock Pulse Duration, Low	2.0	—	2.5	—	ns

1. Unless noted otherwise, all parameters use the GRP, Y0, Y1, ORP, and Y0 clock.
2. Refer to Timing Model in this data sheet for further details.
3. Standard 16-bit counter using GRP feedback.
4. Reference Switching Test Conditions section.

Table 2-0030A/2032VE

PRELIMINARY

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External Timing Parameters

Over Recommended Operating Conditions

PARAMETER	TEST COND. ⁴	# ²	DESCRIPTION ¹	-135		-110		UNITS
				MIN.	MAX.	MIN.	MAX.	
t _{pd1}	A	1	Data Propagation Delay, 4PT Bypass, ORP Bypass	---	7.5	---	10.0	ns
t _{pd2}	A	2	Data Propagation Delay	---	10.0	---	13.0	ns
f _{max}	A	3	Clock Frequency with Internal Feedback ³	137	---	111	---	MHz
f _{max} (Ext.)	---	4	Clock Frequency with External Feedback ($\frac{1}{t_{su2} + t_{co1}}$)	100	---	77.0	---	MHz
f _{max} (Tog.)	---	5	Clock Frequency, Max. Toggle	167	---	125	---	MHz
t _{su1}	---	6	GLB Reg. Setup Time before Clock, 4 PT Bypass	---	---	5.5	---	ns
t _{co1}	A	7	GLB Reg. Clock to Output Delay, ORP Bypass	---	4.0	---	5.5	ns
t _{h1}	---	8	GLB Reg. Hold Time after Clock, 4 PT Bypass	0.0	---	0.0	---	ns
t _{su2}	---	9	GLB Reg. Setup Time before Clock	5.5	---	7.5	---	ns
t _{co2}	---	10	GLB Reg. Clock to Output Delay	---	5.5	---	6.5	ns
t _{h2}	---	11	GLB Reg. Hold Time after Clock	0.0	---	0.0	---	ns
t _{r1}	A	12	Ext. Reset Pin to Output Delay	---	10.0	---	13.5	ns
t _{rw1}	---	13	Ext. Reset Pulse Duration	5.0	---	6.5	---	ns
t _{ptoen}	B	14	Input to Output Enable	---	12.0	---	14.5	ns
t _{ptois}	C	15	Input to Output Disable	---	12.0	---	14.5	ns
t _{goeen}	B	16	Global OE Output Enable	---	6.0	---	7.0	ns
t _{goeis}	C	17	Global OE Output Disable	---	6.0	---	7.0	ns
t _{wh}	---	18	External Synchronous Clock Pulse Duration, High	3.0	---	4.0	---	ns
t _{wl}	---	19	External Synchronous Clock Pulse Duration, Low	3.0	---	4.0	---	ns

Table 2-0030B:2032VE

1. Unless noted otherwise, all parameters use the GRP, 2032 XOR path, ORP and Y0 clock.
2. Refer to Timing Model in this data sheet for further details.
3. Standard 16-bit counter using GRP feedback.
4. Reference Switching Test Conditions section.

PRELIMINARY